Docket No.: 050099-0238

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Customer Number: 20277

Shigenobu MAEDA, et al.

Confirmation Number: 6603

Application No.: 10/748,273

Group Art Unit: 2823

Filed: December 31, 2003

Examiner: T. V. Pham

For: METHOD OF MANUFACTURING SEMICONDUCTOR DEVICE HAVING IMPURITY

REGION UNDER ISOLATION REGION (As Amended)

INFORMATION DISCLOSURE STATEMENT

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached form PTO-1449. It is respectfully requested that the references be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

Each non-English language reference was first cited in a corresponding foreign application office action and its relevance discussed therein. A copy of the foreign office action, together with an English language version thereof, is attached for the Examiner's information.

10/748,273

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

McDERMOTT WILL & EMERY LLP

Rechard Res. No. 47,453

Please recognize our Customer No. 20277

as our correspondence address.

For Stephen A. Becker Registration No. 26,527

600 13th Street, N.W. Washington, DC 20005-3096 Phone: 202.756.8000 SAB:gav

Facsimile: 202.756.8087 **Date: June 10, 2005**

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^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.